N-Channel Shielded Gate POWERTRENCH[®] MOSFET

80 V, 126 A, 4.0 mΩ

General Description

This N-Channel MV MOSFET is produced using ON Semiconductor's advanced PowerTrench process that incorporates Shielded Gate technology. This process has been optimized to minimize on-state resistance and yet maintain superior switching performance with best in class soft body diode.

Features

- Shielded Gate MOSFET Technology
- Max $r_{DS(on)} = 4.0 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 44 \text{ A}$
- Max $r_{DS(on)} = 12.5 \text{ m}\Omega$ at $V_{GS} = 6 \text{ V}$, $I_D = 22 \text{ A}$
- 50% Lower Qrr than Other MOSFET Suppliers
- Lowers Switching Noise/EMI
- MSL1 Robust Package Design
- 100% UIL Tested
- These Devices are Pb-Free and are RoHS Compliant

Applications

- Primary DC–DC MOSFET
- Synchronous Rectifier in DC–DC and AC–DC
- Motor Drive
- Solar

MAXIMUM RATINGS ($T_A = 25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Value	Unit	
V _{DS}	Drain to Source Voltage	80	V	
V _{GS}	Gate to Source Voltage	±20	V	
ID	Drain Current: Continuous, $T_C = 25^{\circ}C$ (Note 5) Continuous, $T_C = 100^{\circ}C$ (Note 5) Continuous, $T_A = 25^{\circ}C$ (Note 1a) Pulsed (Note 4)	126 80 18 637	A	
E _{AS}	Single Pulse Avalanche Energy (Note 3)	486	mJ	
P _D	Power Dissipation: $T_C = 25^{\circ}C$ $T_A = 25^{\circ}C$ (Note 1a)	125 2.5	W	
T_J, T_{STG}	Operating and Storage Junction Temperature Range	-55 to +150	°C	

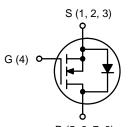
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.



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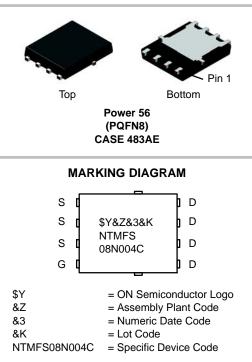
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V _{DS}	R _{DS(ON)} MAX	I _D MAX
80 V	4.0 mΩ @ 10 V	126 A
	12.5 mΩ @ 6 V	



D (5, 6, 7, 8)

N-CHANNEL MOSFET



ORDERING INFORMATION

See detailed ordering and shipping information on page 3 of this data sheet.

THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction to Case	1.0	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	50	

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Test Condition	Min	Тур	Max	Unit
OFF CHARA	ACTERISTICS		-	-	-	-
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \ \mu A, \ V_{GS} = 0 \ V$	80			V
$\Delta {\rm BV}_{\rm DSS}$ / $\Delta {\rm T}_{\rm J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu\text{A}$, referenced to 25°C		40		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 64 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			1	μΑ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20$ V, $V_{DS} = 0$ V			±100	nA
ON CHARA	CTERISTICS					
V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \ \mu A$	2.0	3.1	4.0	V
${\Delta V_{GS(th)} \over /\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250 \ \mu\text{A}$, referenced to 25°C		-8.3		mV/°C
r _{DS(on)}	Static Drain to Source On Resistance	V _{GS} = 10 V, I _D = 44 A		3.4	4.0	mΩ
		V _{GS} = 6 V, I _D = 22 A		5.2	12.5	
		V_{GS} = 10 V, I_D = 44 A, T_J = 125°C		5.8	7.8	
9fs	Forward Transconductance	V _{DS} = 5 V, I _D = 44 A		98		S
DYNAMIC C	HARACTERISTICS		•			
C _{iss}	Input Capacitance	V_{DS} = 40 V, V_{GS} = 0 V, f = 1 MHz		3035	5100	pF
C _{oss}	Output Capacitance			940	1580	pF
C _{rss}	Reverse Transfer Capacitance			27	50	pF
Rg	Gate Resistance		0.1	1.1	2.3	Ω
SWITCHING	CHARACTERISTICS					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 40 \text{ V}, \text{ I}_{D} = 44 \text{ A}, \text{ V}_{GS} = 10 \text{ V},$		17	30	ns
t _r	Rise Time	$R_{GEN} = 6 \ \Omega$		6	12	ns
t _{d(off)}	Turn-Off Delay Time			25	40	ns
t _f	Fall Time			4	10	ns
Qg	Total Gate Charge	$V_{GS} = 0 V$ to 10 V, $V_{DD} = 40 V$, I _D = 44 A		39	66	nC
		V_{GS} = 0 V to 6 V, V_{DD} = 40 V, I_{D} = 44 A		25	41	nC
Q _{gs}	Gate to Source Charge	V _{DD} = 40 V, I _D = 44 A	1	13		nC
Q _{gd}	Gate to Drain "Miller" Charge	V _{DD} = 40 V, I _D = 44 A	1	7		nC
Q _{oss}	Output Charge	$V_{DD} = 40 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$		55		nC
Q _{sync}	Total Gate Charge Sync.	V _{DS} = 0 V, I _D = 44 A		35		nC

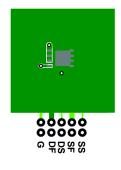
ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted) (continued)

Symbol	Parameter	Test Condition	Min	Тур	Max	Unit	
DRAIN-SOURCE DIODE CHARACTERISTICS							
V _{SD}	Source to Drain Diode Forward Voltage	V _{GS} = 0 V, I _S = 2.1 A (Note 2)		0.7	1.2	V	
		V _{GS} = 0 V, I _S = 44 A (Note 2)		0.8	1.3		
t _{rr}	Reverse Recovery Time	I _F = 22 A, di/dt = 300 A/μs		26	41	ns	
Q _{rr}	Reverse Recovery Charge	1		48	76	nC	
t _{rr}	Reverse Recovery Time	I _F = 22 A, di/dt = 1000 A/μs		19	31	ns	
Q _{rr}	Reverse Recovery Charge			108	174	nC	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

NOTES:

1. $R_{\theta JA}$ is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 × 1.5 in. board of FR-4 material. $R_{\theta CA}$ is determined by the user's board design.



a) 50°C/W when mounted on a 1 in² pad of 2 oz copper.



b) 125°C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%.
- 3. E_{AS} of 486 mJ is based on starting $T_J = 25^{\circ}$ C; N-ch: L = 3 mH, $I_{AS} = 18$ A, $V_{DD} = 80$ V, $V_{GS} = 10$ V. 100% test at L = 0.1 mH, $I_{AS} = 57$ A. 4. Pulsed ld please refer to Figure 11 SOA graph for more details.
- 5. Computed continuous current limited to Max Junction Temperature only, actual continuous current will be limited by thermal & electro-mechanical application board design.

PACKAGE MARKING AND ORDERING INFORMATION

Device	Marking	Package	Reel Size	Tape Width	Quantity
NTMFS08N004C	NTMFS08N004C	Power 56 (PQFN8) (Pb-Free / Halogen Free)	13″	12 mm	3000 units

TYPICAL CHARACTERISTICS

(T_J = 25°C unless otherwise noted)

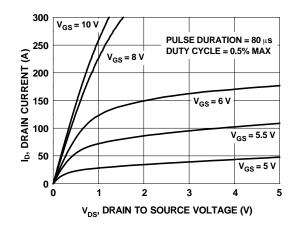


Figure 1. On Region Characteristics

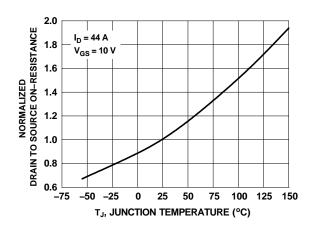


Figure 3. Normalized On-Resistance vs. Junction Temperature

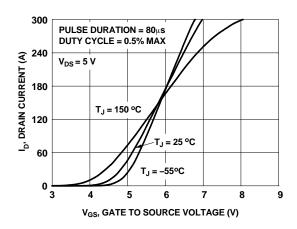


Figure 5. Transfer Characteristics

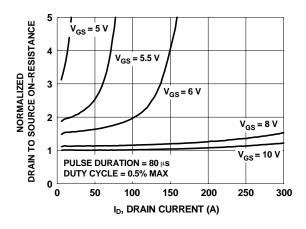
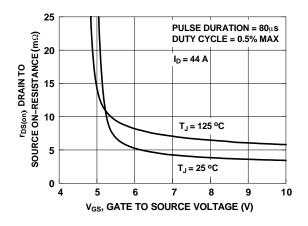
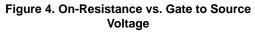
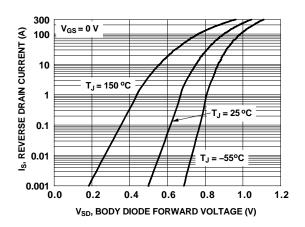


Figure 2. Normalized On-Resistance vs. Drain Current and Gate Voltage









TYPICAL CHARACTERISTICS

(T_J = 25°C unless otherwise noted)

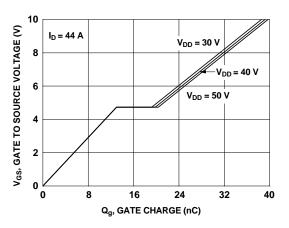
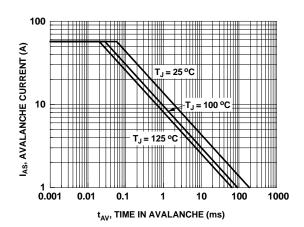


Figure 7. Gate Charge Characteristics





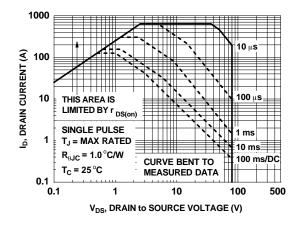


Figure 11. Forward Bias Safe Operating Area

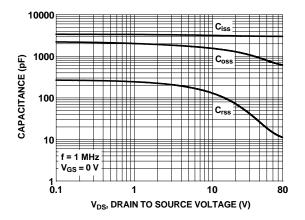


Figure 8. Capacitance vs. Drain to Source Voltage

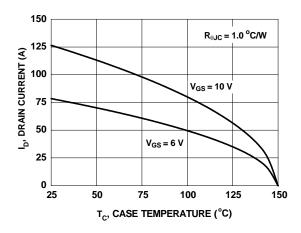
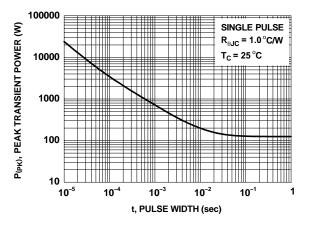


Figure 10. Maximum Continuous Drain Current vs. Case Temperature





TYPICAL CHARACTERISTICS

 $(T_J = 25^{\circ}C \text{ unless otherwise noted})$

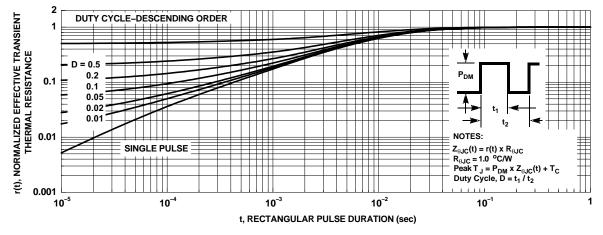
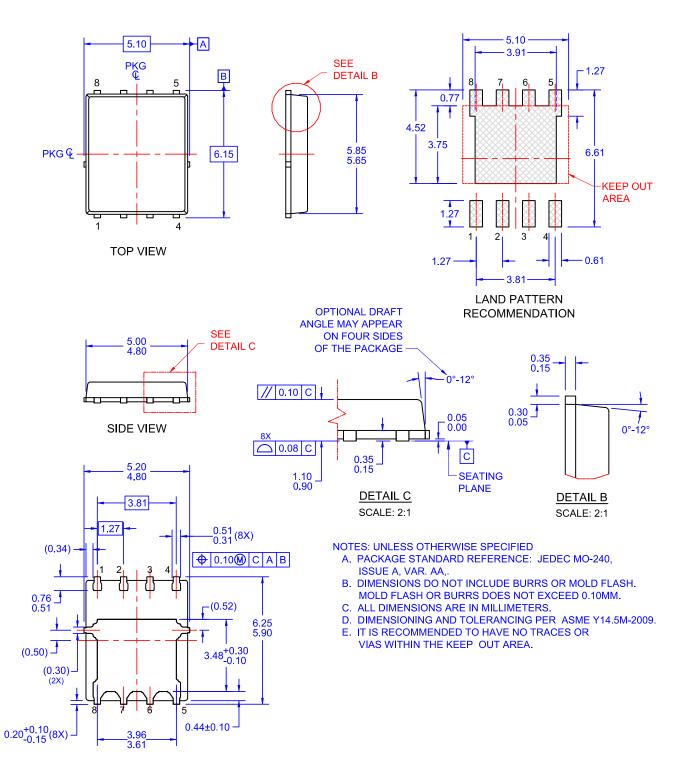


Figure 13. Junction-to-Case Transient Thermal Response Curve

PACKAGE DIMENSIONS

PQFN8 5X6, 1.27P CASE 483AE ISSUE A



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